Progress of IEEE-IEC Joint Standardization on Superconducting Electronics Devices: Report on the Standardization Session at IWSSD2016

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***Abstract* – The report on the Standardization Session at the IWSSD 2016 Workshop is prepared as a technical paper. At the session covered were:**

- **Organization of the IEC–IEEE standardization effort in superconducting electronics, responsibilities and appointments.**
- **Registered graphical symbols in superconducting electronics, including explanation of Josephson junction symbol design logic – in analogy to semiconductor symbols.**
- **Round robin tests on HTS and LTS Josephson junctions, junction arrays and SQUIDs.**
- **A proposal for standardization of superconducting strip type photon detectors (SSPD).**
- **A road map for standardization of superconducting electronics.**

***Keywords (Index Terms)* – Superconducting electronics, standardization, superconducting sensor, superconducting detector, IEC, IEEE, graphical symbols, round robin test, Josephson junction, JJ, Josephson junction array, superconducting quantum interference device, SQUID.**

IEEE/CSC & ESAS SUPERCONDUCTIVITY NEWS FORUM (global edition), April 2017.
Received March 16, 2017; Accepted April 17, 2017. Reference No. ST575, Category 4.